

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Yoshitaka SASAGO et al.

Appln. No.:

Filed: HEREWITH

For: NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND  
MANUFACTURING METHOD THEREOF

\* \* \*

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Applicants wish to make of record the documents cited in prior Application No. 10/166,145 filed June 11, 2002, whether cited by Applicants or by the Patent Office. The documents are listed on the attached Form PTO-1449.

Respectfully submitted,

MWS:lmb

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November 6, 2003

FORM PTO-1449				Atty. Docket No. XA-9693A	Appln. No.		
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>							
				Applicant Yoshitaka SASAGO et al.			
				Filing Date HEREWITH	Group		
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA	<b>5,095,344</b>	03/10/92	Harari (corrs. to JP 2694618)	357	23.5	
	AB	<b>5,739,569</b>	4/98	Chen	257	322	
	AC	<b>5,773,863</b>	6/98	Burr et al.	257	316	
	AD	<b>6,492,690</b>	12/02	Ueno et al.	257	316	
	AE	<b>4,561,004</b>	12/85	Kuo et al.	257	319	
	AF	<b>4,745,083</b>	5/88	Huie	257	316	
	AG	<b>5,455,792</b>	10/95	Yi	257	345	
	AH	<b>5,640,032</b>	6/97	Tomioka	257	316	
	AI						
<b>FOREIGN PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AJ	<b>2694618</b>	09/12/97	Japan			No
	AK	<b>9-321157</b>	12/12/97	Japan			Abstract
	AL						
	AM						
	AN						
	AO						
<b>OTHER</b> (including author, title, date, pertinent pages, etc.)							
	AP	<b>"Ohyo Butsuri" (or APPLIED PHYSICS), The Japan Society of Applied Physics, Vol. 65, No. 11, November 10, 1996, pp. 1114-1124.</b>					
	AQ	<b>K. Naruke et al., "A New Flash-Erase EEPROM Cell with a Sidewall Select-Gate on its Source Side", IEDM, 1989, pp. 603-606.</b>					
	AR						
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							